# Protected Power MOSFET 2.6 Amps, 52 Volts

N-Channel, Logic Level, Clamped MOSFET w/ ESD Protection in a SOT-223 Package

#### **Benefits**

- High Energy Capability for Inductive Loads
- Low Switching Noise Generation

#### **Features**

- Diode Clamp Between Gate and Source
- ESD Protection HBM 5000 V
- Active Over-Voltage Gate to Drain Clamp
- Scalable to Lower or Higher R<sub>DS(on)</sub>
- Internal Series Gate Resistance

## **Applications**

Automotive and Industrial Markets:
 Solenoid Drivers, Lamp Drivers, Small Motor Drivers

# **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage Internally Clamped	$V_{DSS}$	52–59	V
Gate-to-Source Voltage - Continuous	V <sub>GS</sub>	±12	V
	I <sub>D</sub> I <sub>DM</sub>	2.6 10	Α
Total Power Dissipation @ T <sub>A</sub> = 25°C (Note 1)	P <sub>D</sub>	1.69	W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 V, $I_{D(pk)}$ = 1.17 A, $V_{GS}$ = 10 V, L = 160 mH, $R_{G}$ = 25 $\Omega$ )	E <sub>AS</sub>	110	mJ
Thermal Resistance  – Junction–to–Ambient (Note 1)  – Junction–to–Ambient (Note 2)	R <sub>θJA</sub> R <sub>θJA</sub>	74 169	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 10 Sec.	TL	260	°C

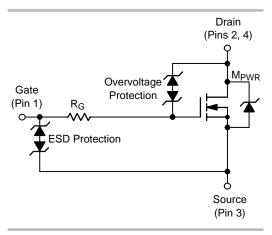
1. When surface mounted to an FR4 board using 1" pad size, (Cu area 1.127 in²)



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## http://onsemi.com

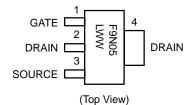
V <sub>DSS</sub> (Clamped)	R <sub>DS(ON)</sub> TYP	I <sub>D</sub> MAX		
52 V	107 mΩ	2.6 A		





SOT-223 CASE 318E STYLE 3

#### **MARKING DIAGRAM**



F9N05 = Specific Device Code L = Location Code WW = Work Week

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>		
NIF9N05CLT1	SOT-223	1000/Tape & Reel		
NIF9N05CLT3	SOT-223	4000/Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

When surface mounted to an FR4 board using minimum recommended pad size, (Cu area 0.412 in<sup>2</sup>)

# MOSFET ELECTRICAL CHARACTERISTICS ( $T_J = 25$ °C unless otherwise noted)

Characterist	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS					•	
Drain-to-Source Breakdown Voltage (Note 3) (V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1.0 mA) Temperature Coefficient (Negative)		V <sub>(BR)DSS</sub>	52	55 -9.3	59	V mV/°C
Zero Gate Voltage Drain Current $(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V})$ $(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125^{\circ}\text{C})$		I <sub>DSS</sub>			10 25	μΑ
Gate-Body Leakage Current $(V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V})$ $(V_{GS} = \pm 14 \text{ V}, V_{DS} = 0 \text{ V})$		I <sub>GSS</sub>		±22	±10	μΑ
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage (Note 3) $(V_{DS} = V_{GS}, I_D = 100 \ \mu\text{A})$ Threshold Temperature Coefficient (Negative)		V <sub>GS(th)</sub>	1.3	1.75 -4.1	2.5	V mV/°C
Static Drain-to-Source On-Resistance (Note 3) $ (V_{GS} = 3.5 \text{ V}, I_D = 0.6 \text{ A}) $ $ (V_{GS} = 4.0 \text{ V}, I_D = 1.5 \text{ A}) $ $ (V_{GS} = 10 \text{ V}, I_D = 2.6 \text{ A}) $		R <sub>DS(on)</sub>		190 165 107	380 200 125	mΩ
Forward Transconductance (Note 3) (V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2.6 A)		9FS		3.8		Mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance		C <sub>iss</sub>		155	250	pF
Output Capacitance	$V_{DS} = 35 \text{ V}, V_{GS} = 0 \text{ V},$ f = 10 kHz	C <sub>oss</sub>		60	100	
Transfer Capacitance		C <sub>rss</sub>		25	40	
Input Capacitance	V = 25 V V = 0 V			170		pF
Output Capacitance				70		
Transfer Capacitance	- -	C <sub>rss</sub>		30		

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

# MOSFET ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)

Characteristic			Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (Note 4)			•			
Turn-On Delay Time		t <sub>d(on)</sub>		275	465	ns
Rise Time	V <sub>GS</sub> = 4.5 V, V <sub>DD</sub> = 40 V,	t <sub>r</sub>		1418	2400	
Turn-Off Delay Time	$I_D = 2.6 \text{ A}, R_D = 15.4 \Omega$	t <sub>d(off)</sub>		780	1320	
Fall Time		t <sub>f</sub>		1120	1900	
Turn-On Delay Time		t <sub>d(on)</sub>		242		ns
Rise Time	V <sub>GS</sub> = 4.5 V, V <sub>DD</sub> = 40 V,	t <sub>r</sub>		1165		
Turn-Off Delay Time	$I_D = 1.0 \text{ A}, R_D = 40 \Omega$	t <sub>d(off)</sub>		906		
Fall Time		t <sub>f</sub>		1273		
Turn-On Delay Time		t <sub>d(on)</sub>		107		ns
Rise Time	V <sub>GS</sub> = 10 V, V <sub>DD</sub> = 15 V,	t <sub>r</sub>		290		
Turn-Off Delay Time	$I_D = 2.6 \text{ A}, R_D = 5.8 \Omega$	t <sub>d(off)</sub>		1540		
Fall Time		t <sub>f</sub>		1000		
Gate Charge		Q <sub>T</sub>		4.5	7.0	nC
	$V_{GS} = 4.5 \text{ V}, V_{DS} = 40 \text{ V},$ $I_{D} = 2.6 \text{ A (Note 3)}$	Q <sub>1</sub>		0.9		
		Q <sub>2</sub>		2.6		
Gate Charge	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 1.5 \text{ A (Note 3)}$	Q <sub>T</sub>		3.9		nC
		Q <sub>1</sub>		1.0		
	.g .i.e.v.(.i.e.e.e,	Q <sub>2</sub>		1.7		
SOURCE-DRAIN DIODE CHARACTERIST	ics					
Forward On-Voltage	$I_S = 2.6 \text{ A}, V_{GS} = 0 \text{ V (Note 3)}$ $I_S = 2.6 \text{ A}, V_{GS} = 0 \text{ V}, T_J = 125^{\circ}\text{C}$	V <sub>SD</sub>		0.81 0.66	1.5	V
Reverse Recovery Time	$I_S = 1.5 \text{ A}, V_{GS} = 0 \text{ V},$ $dI_S/dt = 100 \text{ A/}\mu\text{s} \text{ (Note 3)}$	t <sub>rr</sub>		730		ns
		t <sub>a</sub>		200		
	ang at 100 reps (11010 0)	t <sub>b</sub>		530		
Reverse Recovery Stored Charge		$Q_{RR}$		6.3		μС
ESD CHARACTERISTICS		•		•	•	
Electro-Static Discharge Capability	Human Body Model (HBM)	ESD	5000			V
	Machine Model (MM)		500			

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

## **TYPICAL PERFORMANCE CURVES**

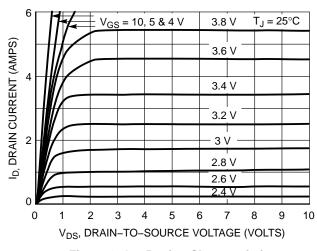


Figure 1. On-Region Characteristics

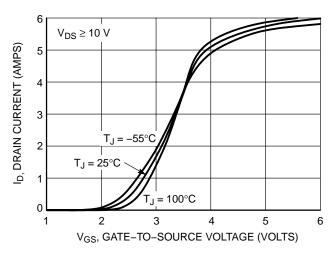


Figure 2. Transfer Characteristics

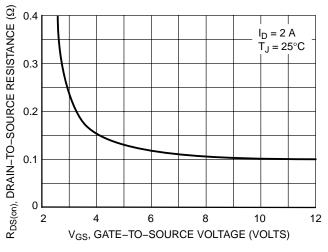


Figure 3. On-Resistance vs. Gate-to-Source Voltage

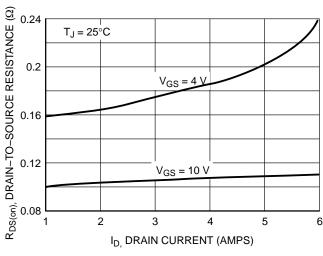


Figure 4. On-Resistance vs. Drain Current and **Gate Voltage** 

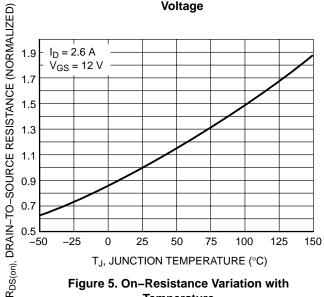


Figure 5. On-Resistance Variation with **Temperature** 

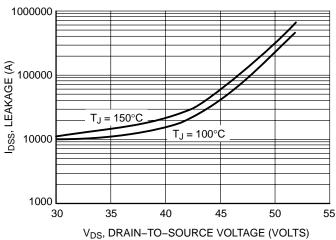
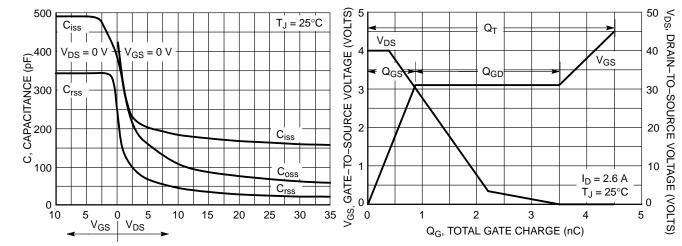


Figure 6. Drain-to-Source Leakage Current vs. Voltage

## **TYPICAL PERFORMANCE CURVES**



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

Figure 8. Gate-to-Source Voltage vs. Total Gate Charge

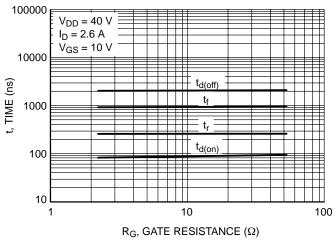


Figure 9. Resistance Switching Time Variation vs. Gate Resistance

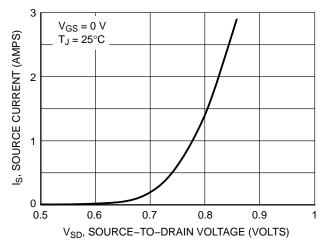
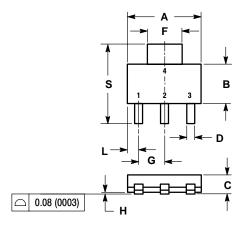
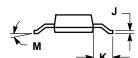


Figure 10. Diode Forward Voltage vs. Current

#### PACKAGE DIMENSIONS

SOT-223 CASE 318E-04 ISSUE K





#### NOTES

- DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.249	0.263	6.30	6.70	
В	0.130	0.145	3.30	3.70	
С	0.060	0.068	1.50	1.75	
D	0.024	0.035	0.60	0.89	
F	0.115	0.126	2.90	3.20	
G	0.087	0.094	2.20	2.40	
Н	0.0008	0.0040	0.020	0.100	
J	0.009	0.014	0.24	0.35	
K	0.060	0.078	1.50	2.00	
L	0.033	0.041	0.85	1.05	
M	0 °	10 °	0 °	10°	
S	0.264	0.287	6.70	7.30	

# STYLE 3: PIN 1. GATE

- - 2. DRAIN 3. SOURCE

  - 4. DRAIN

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